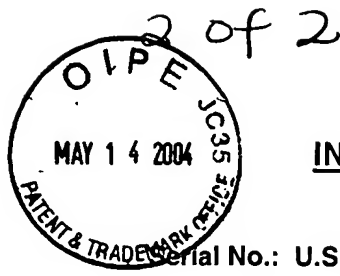


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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: U.S.S.N. 10/676,393

Inventor: Thomas Van Steenkiste, et al.

Title: KINETIC SPRAYED ELECTRICAL CONTACTS ON CONDUCTIVE SUBSTRATES

Filed: October 1, 2003

Art Unit: 1762

ATTORNEY DOCKET: DP-300377

Examiner: Unknown

CERTIFICATE OF MAILING

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STATEMENT ACCOMPANYING
INFORMATION DISCLOSURE STATEMENT

Applicant(s) requests the Examiner to consider and make of record the reference(s) and/or information disclosed herein or on the attached PTO 1449.

CHECK ONE: (A, B, or C.)

☒ A. This statement is submitted within 1) three months after the filing date (even if after the first action); or 2) within three months of the date of entry of the national stage or 3) before the mailing date of a first Office Action on the merits. No fee or statement is required.

☐ B. This statement is submitted after the period specified in para. A, but before Final Office Action or Notice of Allowance or the close of prosecution.

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☐ 1. I hereby state that each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or



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☐ 2. I hereby state that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the certification after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of the information disclosure statement.

☐ 3. Charge the \$180 fee set forth in 37 CFR §1.17(p) to Delphi Technologies, Inc. Deposit Account No. 50-0831.

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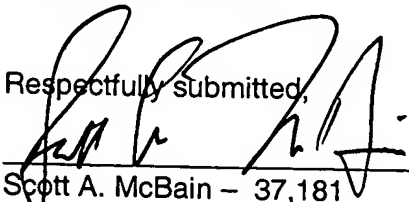
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If any additional fee or any additional amount of fee be required in connection with this Information Disclosure Statement, Applicant respectfully requests that such fee or amount of fee be charged to Delphi Technologies, Inc. Deposit Account No. 50-0831.

Respectfully submitted,



Scott A. McBain – 37,181
Delphi Technologies, Inc.
Telephone (248) 813-1235

enc: PTO 1449 and references

INFORMATION DISCLOSURE CITATION WITH DOCUMENT COPIES



Atty. Docket No. DP-300377	Serial No. 10/676393
Applicant THOMAS HUBERT VAN STEENKISTE	
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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